

Notice of References Cited

Application/Control No.

10/578,028

Applicant(s)/Patent Under
Reexamination
SHIN ET AL.

Examiner

THANH-NHAN P. NGUYEN

Art Unit

2871

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0145684	10-2002	Watanabe et al.	349/51
*	B	US-5,893,621	04-1999	Sekiguchi, Kanetaka	349/51
*	C	US-6,243,062	06-2001	den Boer et al.	345/91
*	D	US-6,593,991	07-2003	Ishimoto, Yoshihisa	349/139
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.